

## 1. Description

MD23N50, the silicon N-channel Enhanced MOSFETs, is obtained by advanced MOSFET technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor is suitable device for SMPS, high speed switching and general purpose applications.

### KEY CHARACTERISTICS

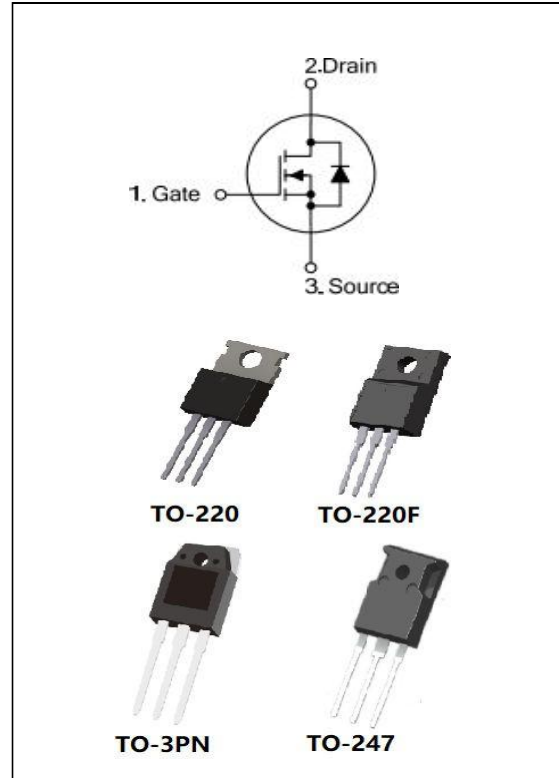
Parameter	Value	Unit
$V_{DS@Tj,max}$	500	V
$I_D$	23	A
$R_{DS(ON),Typ}$	0.23	$\Omega$
$Q_g,Typ$	56	nC

### FEATURES

- Fast Switching
- Low  $C_{rss}$  (typical 18pF)
- 100% avalanche tested
- Improved dv/dt capability
- RoHS product

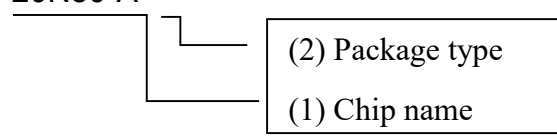
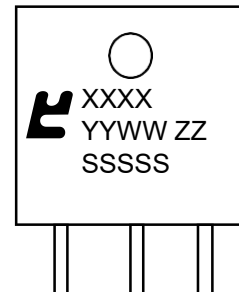
### APPLICATIONS

- High frequency switching mode power supply



### ORDERING INFORMATION

Ordering Codes	Package	Product Code	Packing
MP23N50	TO-220	23N50	Tube
MPF23N50	TO-220F		Tube
MD23N50	TO-3PN		Tube
MD23N50	TO-247		Tube

<p>20N50-A</p>  <p>(1) 23N50:500V 23A  (2) A:TO-220F P:TO-220  W:TO-3PN F:TO-247</p>	 <p>XXXX. Product Code  YYWW. Year&amp;Week  ZZ. Assembly Code  SSSSS. Lot Code</p>
---	---

## 2. ABSOLUTE RATINGS

at  $T_C = 25^\circ\text{C}$ , unless otherwise specified

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-to-Source Voltage	500	V
$I_D$	Continuous Drain Current	23	A
	Continuous Drain Current $T_C = 100^\circ\text{C}$	12.6	A
$I_{DM}$	Pulsed Drain Current(Note1)	80	A
$V_{GS}$	Gate-to-Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy(Note2)	1200	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ (Note3)	5.0	V/ns
$P_D$	Power Dissipation TO-220, TO-3PN	230	W
	Derating Factor above $25^\circ\text{C}$	1.85	W/ $^\circ\text{C}$
$P_D$	Power Dissipation TO-220F, TO-3PF	48	W
	Derating Factor above $25^\circ\text{C}$	0.38	W/ $^\circ\text{C}$
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	150, $-55$ to $150$	$^\circ\text{C}$
$T_L$	Maximum Temperature for Soldering	300	$^\circ\text{C}$

## 3. Thermal characteristics

### Thermal characteristics (No FullPAK) TO-220\TO-3PN

Symbol	Parameter	RATINGS	Units
$R_{\theta JC}$	Junction-to-Case	0.54	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-Ambient	62.5	$^\circ\text{C}/\text{W}$

### Thermal characteristics (FullPAK) TO-220F\TO-3PF

Symbol	Parameter	RATINGS	Units
$R_{\theta JC}$	Junction-to-Case	2.6	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-Ambient	62.5	$^\circ\text{C}/\text{W}$

## 4. Electrical Characteristics

at  $T_C = 25^\circ\text{C}$ , unless otherwise specified

OFF Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$V_{DSS}$	Drain to Source Breakdown Voltage	$V_{GS}=0V$ , $I_D=250\mu A$	500	--	--	V
$\Delta BV_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu A$ , Reference $25^\circ\text{C}$	--	0.6	--	$V/^\circ\text{C}$
$I_{DSS}$	Drain to Source Leakage Current	$V_{DS} = 500V$ , $V_{GS} = 0V$ , $T_J = 25^\circ\text{C}$	--	--	10	$\mu A$
		$V_{DS} = 400V$ , $V_{GS} = 0V$ , $T_J = 125^\circ\text{C}$	--	--	100	$\mu A$
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS} = +30V$	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS} = -30V$	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V$ , $I_D=10A(\text{Note4})$	--	0.23	0.28	$\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250\mu A(\text{Note4})$	2.0	--	4.0	V
$g_{fs}$	Forward Transconductance	$V_{DS}=20V$ , $I_D = 10A(\text{Note4})$	--	12	--	S

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$R_g$	Gate resistance	$f = 1.0\text{MHz}$	--	1.5	--	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1.0\text{MHz}$	--	1920	--	PF
$C_{oss}$	Output Capacitance		--	290	--	
$C_{rss}$	Reverse Transfer Capacitance		--	18	--	

Switching Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	ID =23A VDD = 250V VGS = 10V RG =20Ω	--	33	--	ns
$t_r$	Rise Time		--	75	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	91	--	
$t_f$	Fall Time		--	83	--	
$Q_g$	Total Gate Charge	ID =23A VDD =400V VGS = 10V	--	56	--	nC
$Q_{gs}$	Gate to Source Charge		--	13	--	
$Q_{gd}$	Gate to Drain ("Miller")Charge		--	20	--	

Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Values			Units
			Min.	Typ.	Max.	
$I_S$	Continuous Source Current (Body Diode)	TC=25 °C	--	--	23	A
$I_{SM}$	Maximum Pulsed Current (Body Diode)		--	--	80	A
$V_{SD}$	Diode Forward Voltage	IS=20A, VGS=0V(Note4)	--	--	1.2	V
$T_{rr}$	Reverse Recovery Time	IS=20A, Tj = 25°C dIF/dt=100A/us, VGS=0V	--	536	--	ns
$Q_{rr}$	Reverse Recovery Charge		--	5668	--	nC
$I_{rrm}$	Reverse Recovery Current		--	21.1	--	A

Note1: Pulse width limited by maximum junction temperature

Note2: L=10mH, VD<sub>s</sub>=50V, Start T<sub>J</sub>=25°C

Note3: ISD =23A, di/dt ≤100A/us, VDD≤BVDS, Start T<sub>J</sub>=25°C

Note4: Pulse width tp≤300μs, δ≤2%

## 5. Characteristics Curves

Figure 1a Safe Operating Area (No FullPAK)

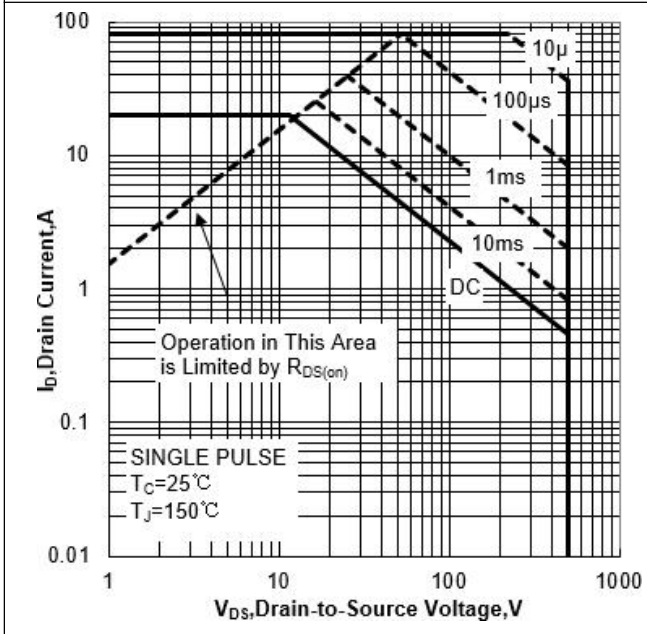


Figure 1b Safe Operating Area (FullPAK)

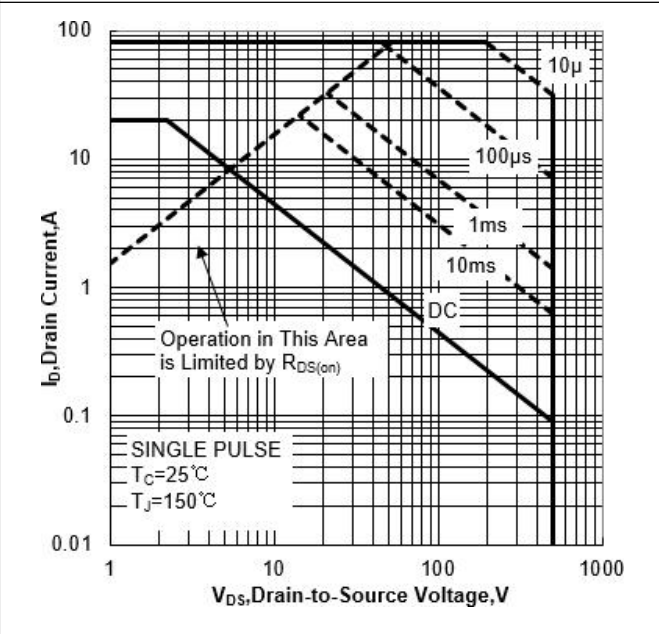


Figure 2a Power Dissipation (No FullPAK)

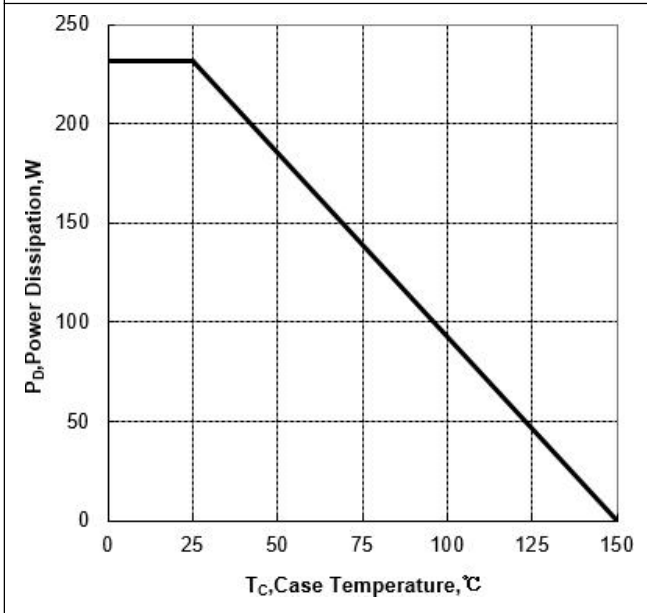


Figure 2b Power Dissipation (FullPAK)

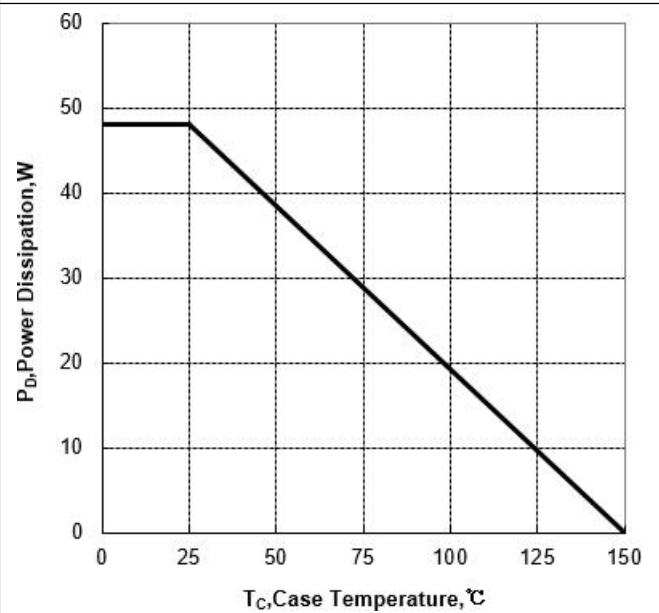


Figure 3a Max Thermal Impedance (No FullPAK)

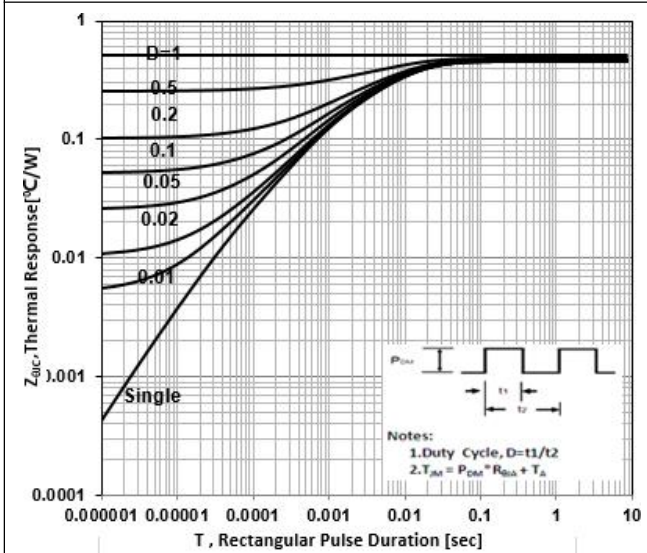


Figure 3b Max Thermal Impedance (FullPAK)

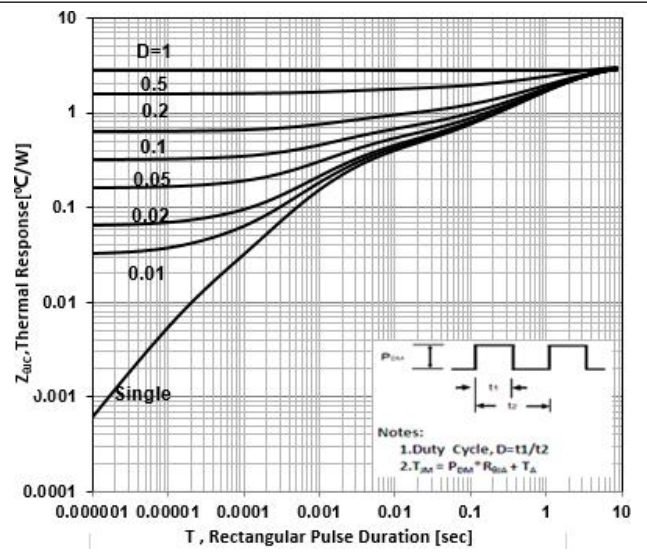


Figure 4 Typical Output Characteristics

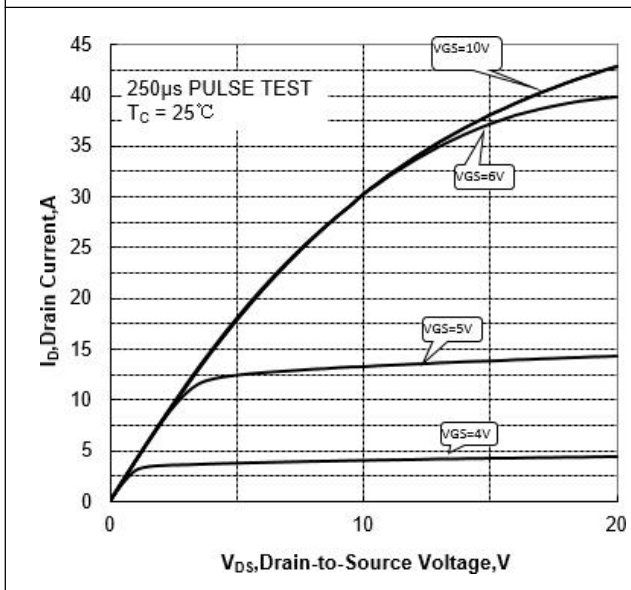
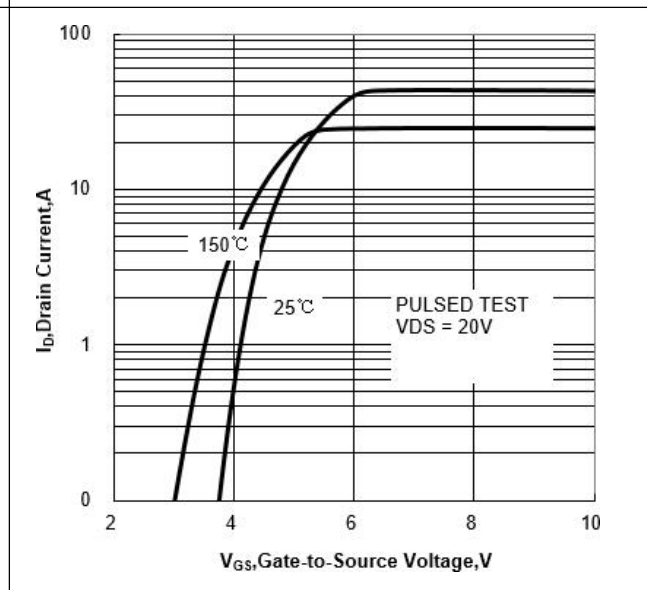
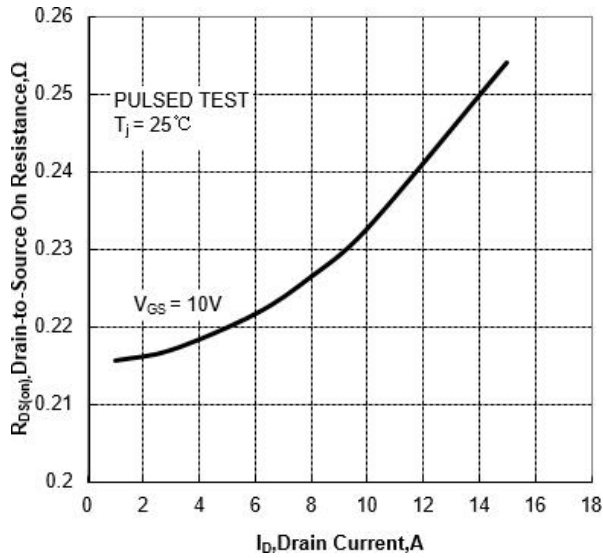


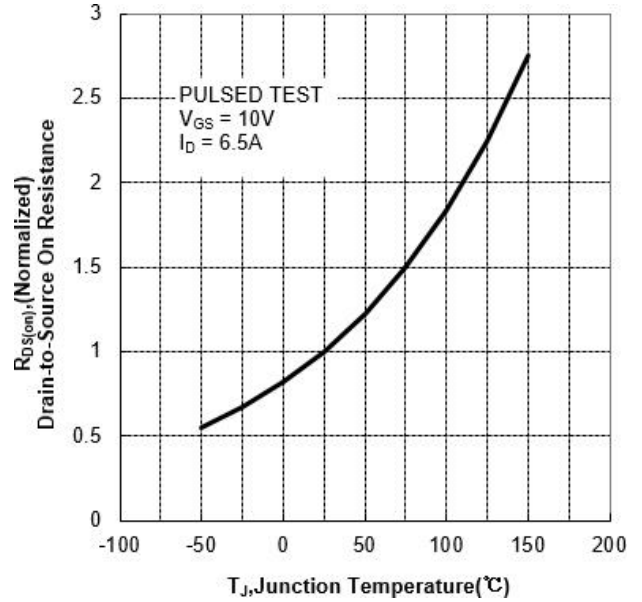
Figure 5 Typical Transfer Characteristics



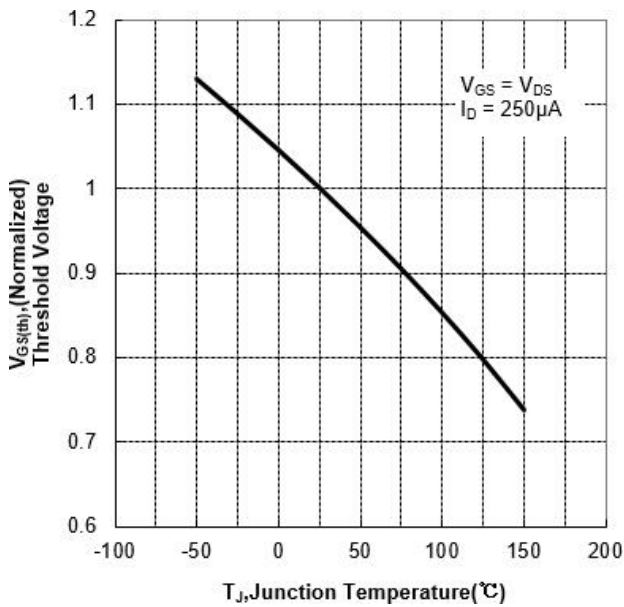
**Figure 6 Typical Drain to Source ON Resistance vs Drain Current**



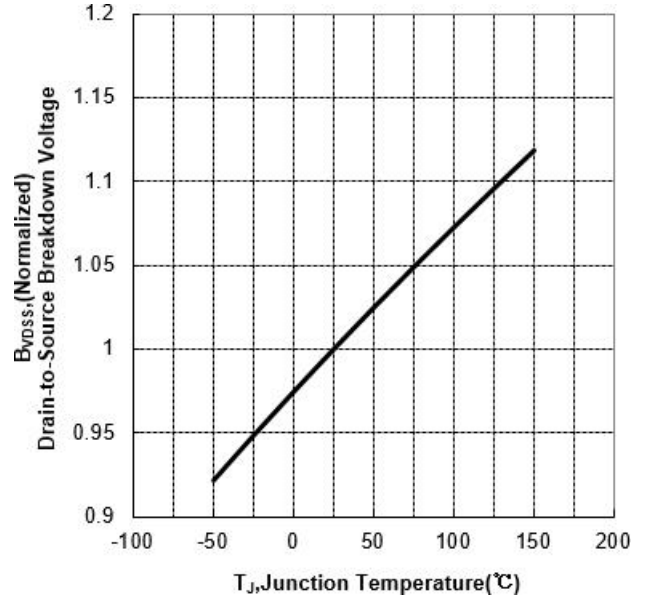
**Figure 7 Typical Drain to Source on Resistance vs Junction Temperature**



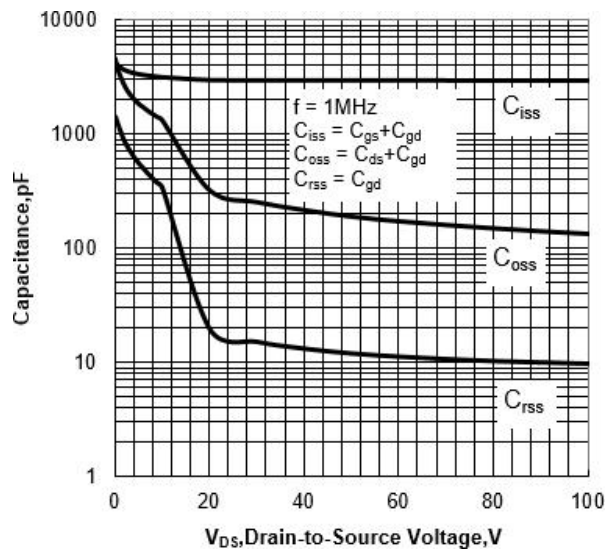
**Figure 8 Typical Threshold Voltage vs Junction Temperature**



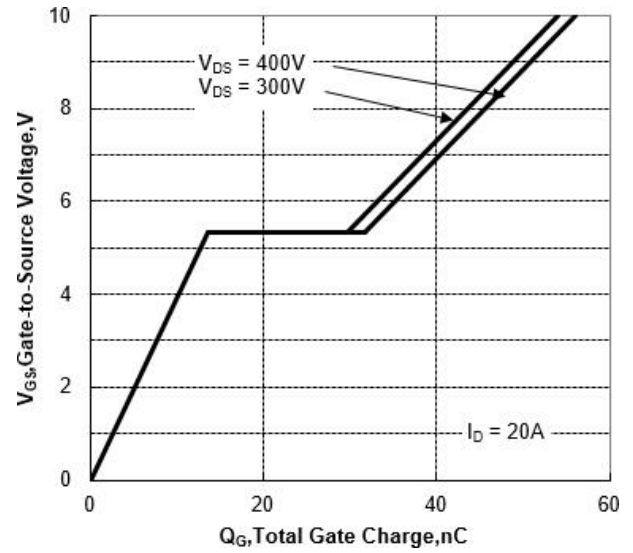
**Figure 9 Typical Breakdown Voltage vs Junction Temperature**



**Figure 10 Typical Capacitance vs Drain to Source Voltage**



**Figure 11 Typical Gate Charge vs Gate to Source Voltage**





## 6. Test Circuit and Waveform

Figure 12 Gate Charge Test Circuit

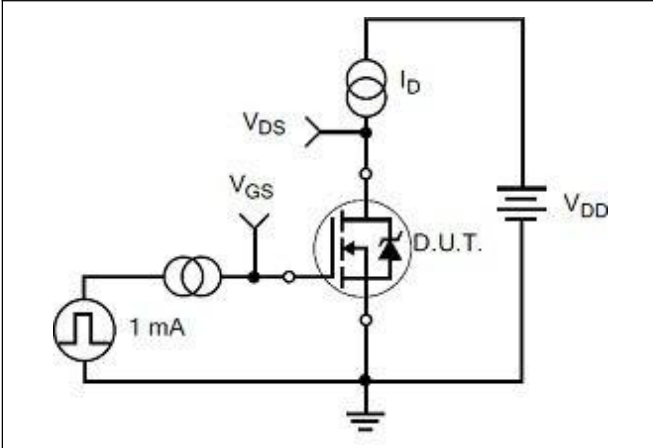


Figure 13 Gate Charge Waveforms

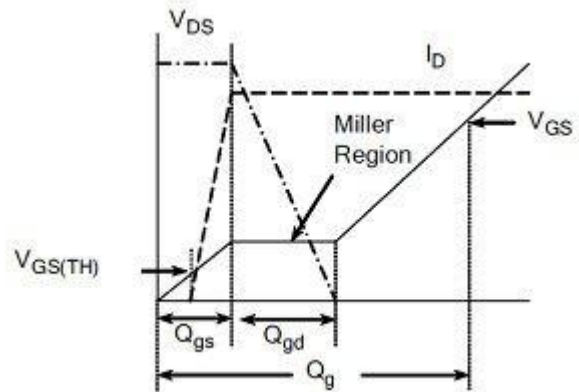


Figure 14 Resistive Switching Test Circuit

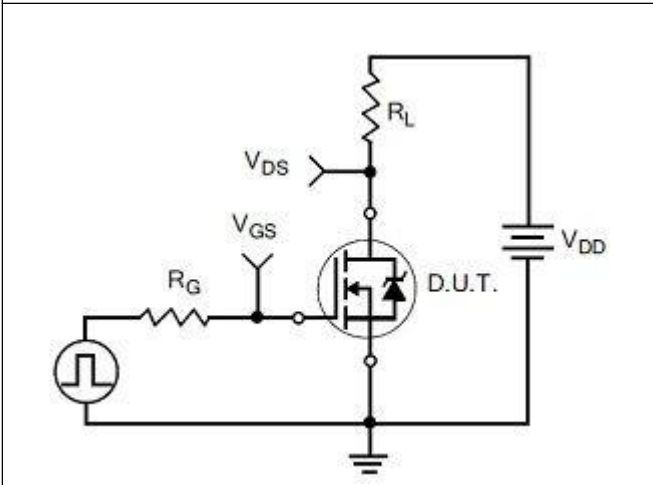


Figure 15 Resistive Switching Waveforms

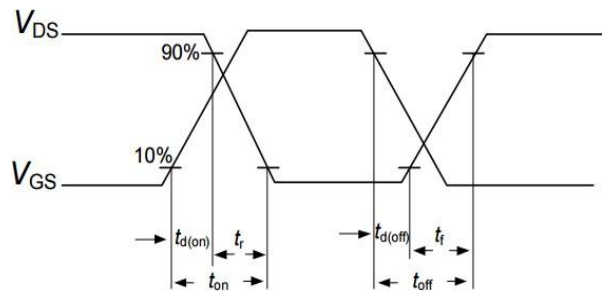


Figure 16 Diode Reverse Recovery Test Circuit

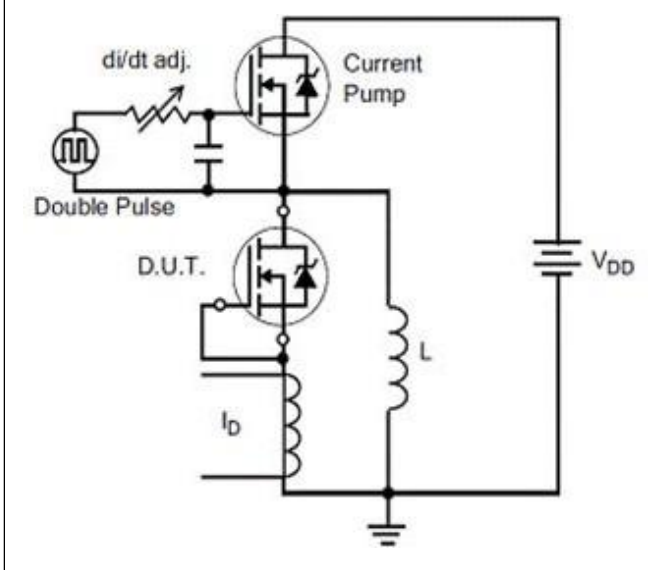


Figure 17 Diode Reverse Recovery Waveform

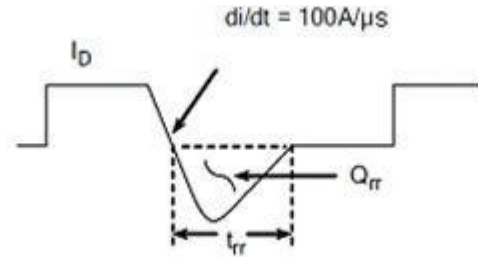


Figure 18 Unclamped Inductive Switching Test Circuit

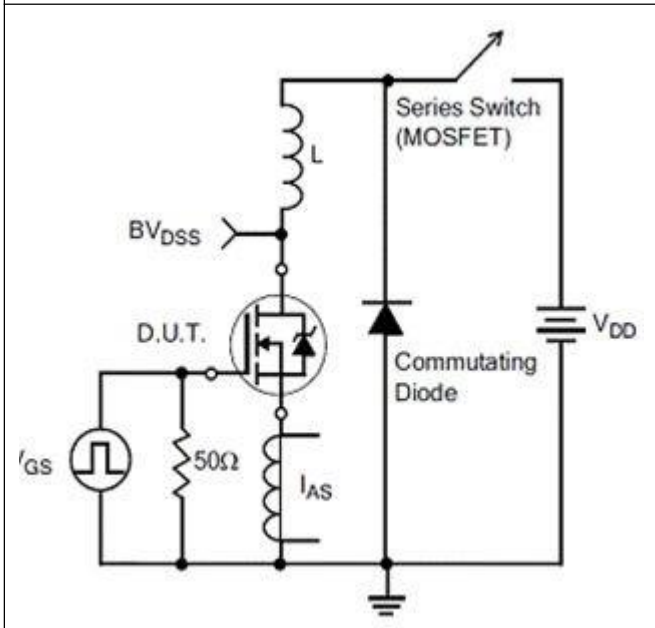
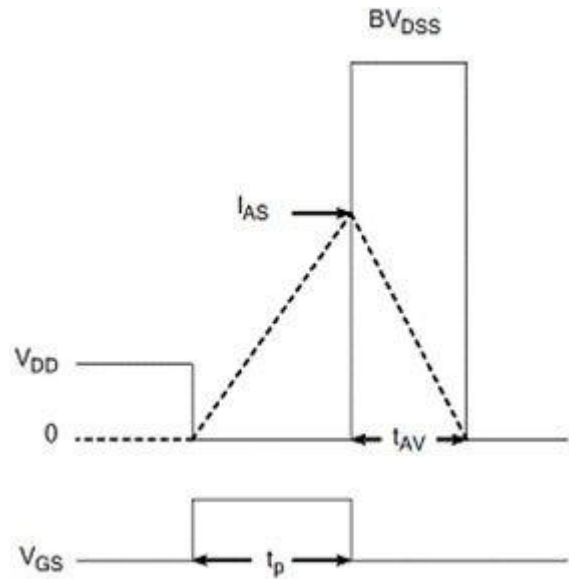
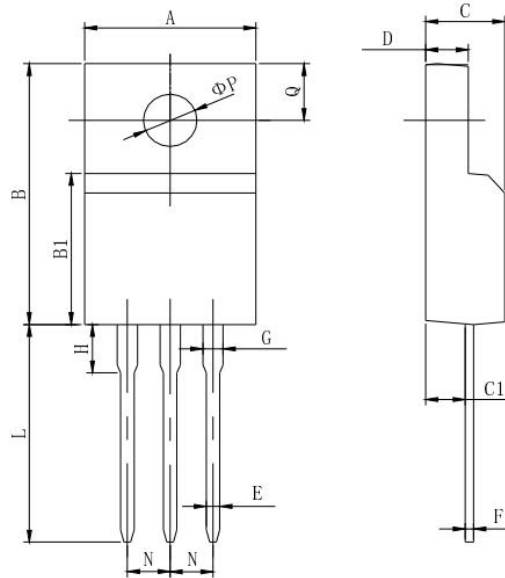


Figure 19 Unclamped Inductive Switching Waveform

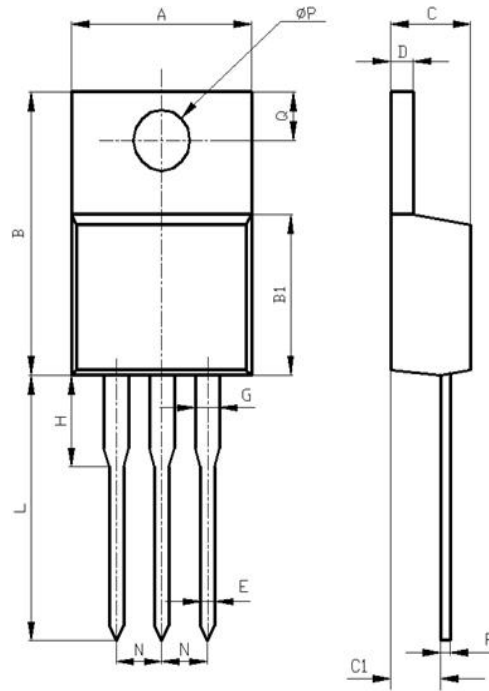


## 7. Package Description



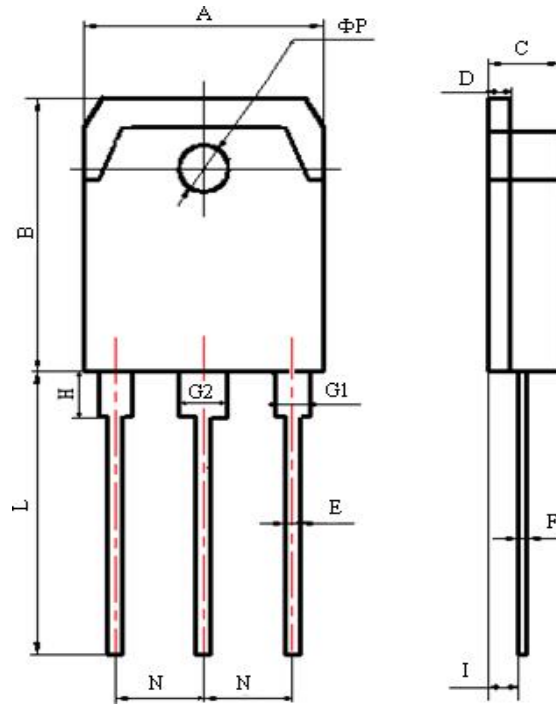
Items	Values(mm)	
	MIN	MAX
A	9.60	10.4
B	15.4	16.2
B1	8.90	9.50
C	4.30	4.90
C1	2.10	3.00
D	2.40	3.00
E	0.60	1.00
F	0.30	0.60
G	1.12	1.42
H	3.40	3.80
	1.60	2.90
L	12.0	14.0
N	2.34	2.74
Q	3.15	3.55
$\Phi P$	2.90	3.30

TO-220F Package



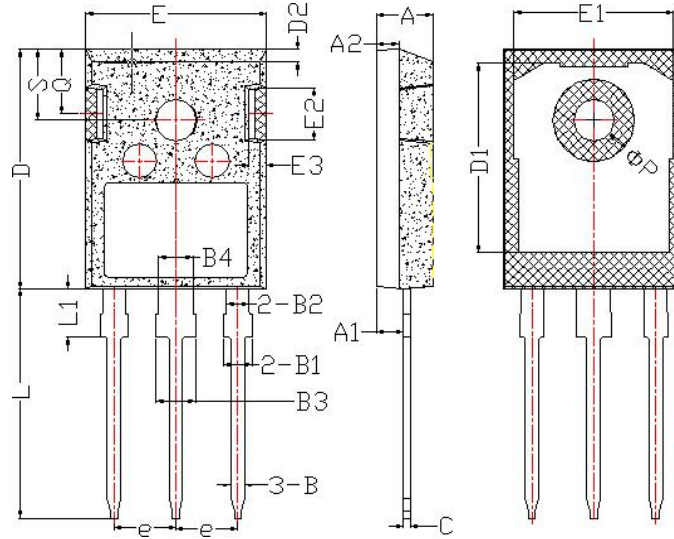
Items	Values(mm)	
	MIN	MAX
A	9.60	10.6
B	15.0	16.0
B1	8.90	9.50
C	4.30	4.80
C1	2.30	3.10
D	1.20	1.40
E	0.70	0.90
F	0.30	0.60
G	1.17	1.37
H	2.70	3.80
L	12.6	14.8
N	2.34	2.74
Q	2.40	3.00
ΦP	3.50	3.90

TO-220 Package



Items	Values(mm)	
	MIN	MAX
A	15.00	16.00
B	19.20	20.60
C	4.60	5.00
D	1.40	1.60
E	0.90	1.10
F	0.50	0.70
G1	2.00	2.20
G2	3.00	3.20
H	3.00	3.70
I	1.20	1.70
	2.70	2.90
L	19.00	21.00
N	5.25	5.65
$\Phi P$	3.10	3.30

TO-3PN Package



Items	Values(mm)	
	MIN	MAX
A	4.6	5.2
A1	2.2	2.6
B	0.9	1.4
B1	1.75	2.35
B2	1.75	2.15
B3	2.8	3.35
B4	2.8	3.15
C	0.5	0.7
D	20.60	21.30
D1	16	18
E	15.5	16.10
E1	13	14.7
E2	3.80	5.3
E3	0.8	2.60
e	5.2	5.7
L	19	20.5
L1	3.9	4.6
ΦP	3.3	3.70
Q	5.2	6.00
S	5.8	6.6

TO-247 Package